Thermal Characteristics

Symbol	Parameter	FGH60T65SHD-F155	Unit
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction to Case, Max.	0.43	°C/W
$R_{\theta JC}(Diode)$	Thermal Resistance, Junction to Case, Max.	1.25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	°C/W

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantit
FGH60T65SHD-F155	FGH60T65SHD	TO-247 G03	Tube	-	-	30

Electrical Characteristics of the IGBT T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	teristics					
BV _{CES}	Collector to Emitter Breakdown Voltage	V _{GE} = 0V, I _C = 1 mA	650	-	-	V
ΔBV _{CES} / ΔΤ _J	Temperature Coefficient of Breakdown Voltage	I _C = 1 mA, Reference to 25°C	-	0.6	-	V/°C
I _{CES}	Collector Cut-Off Current	V _{CE} = V _{CES} , V _{GE} = 0 V	-	-	250	μА
I _{GES}	G-E Leakage Current	V _{GE} = V _{GES} , V _{CE} = 0 V	-	-	±400	nA
On Charac	teristics					
V _{GE(th)}	G-E Threshold Voltage	I _C = 60 mA, V _{CE} = V _{GE}	4.0	5.5	7.5	V
- (-)		I _C = 60 A, V _{GE} = 15 V	-	1.6	2.1	V
V _{CE(sat)}	Collector to Emitter Saturation Voltage	I _C = 60 A, V _{GE} = 15 V, T _C = 175°C	-	2.14	-	V
Dynamic C	haracteristics			'		
C _{ies}	Input Capacitance		-	2980	-	pF
C _{oes}	Output Capacitance	V _{CE} = 30 V _, V _{GE} = 0 V, f = 1MHz	-	110	-	pF
C _{res}	Reverse Transfer Capacitance	1 = 11VID2	-	36	-	pF
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time		-	26	-	ns
t _r	Rise Time		-	48	-	ns
t _{d(off)}	Turn-Off Delay Time	$V_{CC} = 400 \text{ V}, I_{C} = 60 \text{ A},$	-	87	-	ns
t _f	Fall Time	$R_G = 6 \Omega, V_{GE} = 15 V,$	-	47	-	ns
E _{on}	Turn-On Switching Loss	Inductive Load, T _C = 25°C	-	1.69	-	mJ
E _{off}	Turn-Off Switching Loss		-	0.63	-	mJ
E _{ts}	Total Switching Loss		-	2.32	-	mJ
t _{d(on)}	Turn-On Delay Time		-	25	-	ns
t _r	Rise Time	V_{CC} = 400 V, I_{C} = 60 A, R_{G} = 6 Ω , V_{GE} = 15 V, Inductive Load, T_{C} = 175°C	-	60	-	ns
t _{d(off)}	Turn-Off Delay Time		-	93	-	ns
t _f	Fall Time		-	72	-	ns
E _{on}	Turn-On Switching Loss		-	2.54	-	mJ
E _{off}	Turn-Off Switching Loss		-	1.04	-	mJ
E _{ts}	Total Switching Loss		-	3.58	-	mJ

Electrical Characteristics of the IGBT (Continued)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max	Unit
Qg	Total Gate Charge		-	102	-	nC
Q _{ge}	Gate to Emitter Charge	V _{CE} = 400 V, I _C = 60 A, V _{GE} = 15 V	-	18.4	-	nC
Q _{gc}	Gate to Collector Charge		-	37.5	-	nC

Electrical Characteristics of the Diode $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min.	Тур.	Max	Unit
V _{FM}	Diode Forward Voltage	I _E = 30 A	T _C = 25°C	-	2.3	2.7	V
FIVI	Disast simula tellage		T _C = 175°C	-	1.9	-	
E _{rec}	Reverse Recovery Energy		T _C = 175°C	-	50	-	uJ
t _{rr}	Diode Reverse Recovery Time	I _F =30 A, dI _F /dt = 200 A/μs	T _C = 25°C	-	34.6	-	ns
err			T _C = 175°C	-	197	-	
Q _{rr}	Diode Reverse Recovery Charge		T _C = 25°C	-	58.6	-	nC
	2.000 reteroise recording of italige		T _C = 175°C	-	810	ı	

Figure 1. Typical Output Characteristics

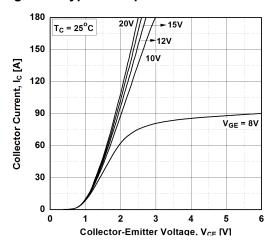


Figure 3. Typical Saturation Voltage Characteristics

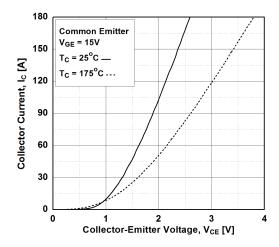


Figure 5. Saturation Voltage vs. V_{GE}

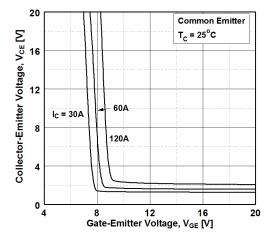


Figure 2. Typical Output Characteristics

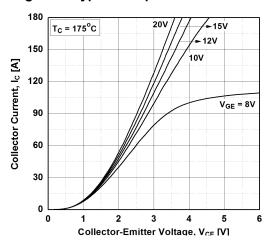


Figure 4. Saturation Voltage vs. Case
Temperature at Variant Current Level

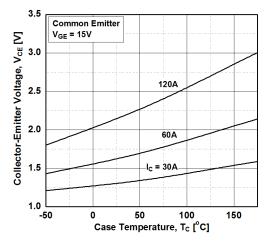


Figure 6. Saturation Voltage vs. V_{GE}

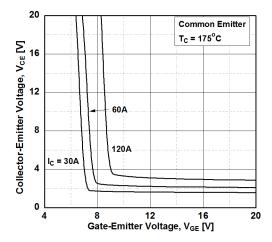


Figure 7. Capacitance Characteristics

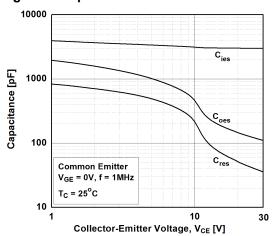


Figure 9. Turn-on Characteristics vs. Gate Resistance

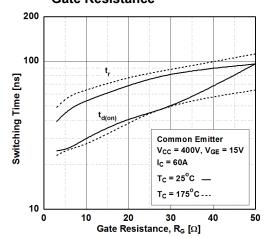


Figure 11. Switching Loss vs.
Gate Resistance

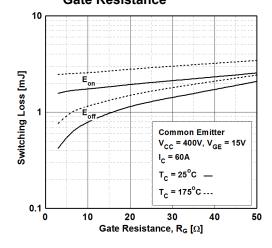


Figure 8. Gate Charge Characteristics

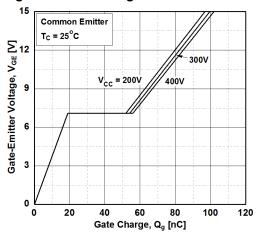


Figure 10. Turn-off Characteristics vs. Gate Resistance

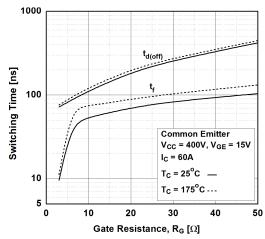


Figure 12. Turn-on Characteristics vs. Collector Current

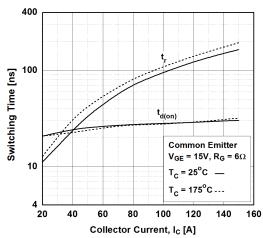


Figure 13. Turn-off Characteristics vs. Collector Current

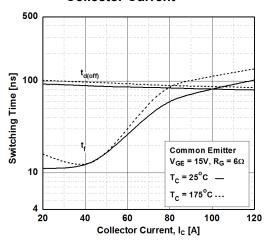


Figure 14. Switching Loss vs. Collector Current

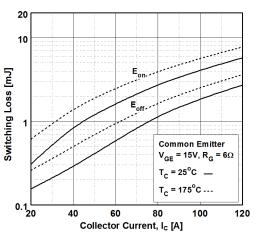


Figure 15. Load Current Vs. Frequency

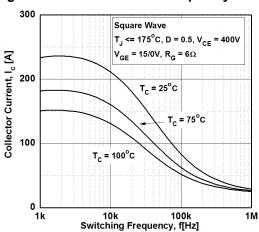


Figure 16. SOA Characteristics

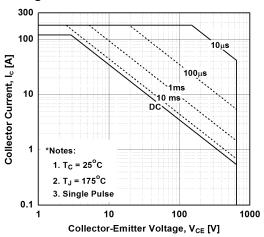


Figure 17. Forward Characteristics

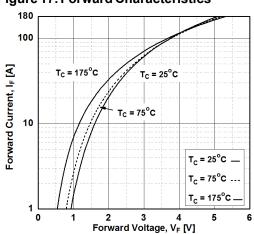


Figure 18. Reverse Recovery Current

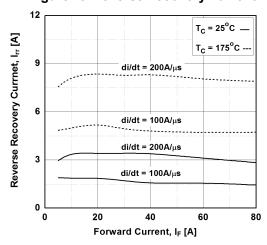


Figure 19. Reverse Recovery Time

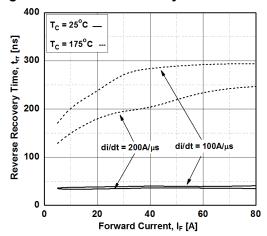


Figure 20. Stored Charge

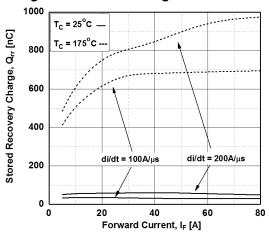


Figure 21.Transient Thermal Impedance of IGBT

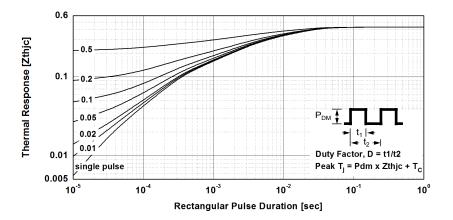
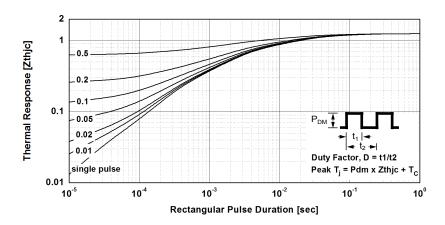


Figure 22.Transient Thermal Impedance of Diode



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